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Sheet 1 of ATTY. DOCKET NO. SERIAL NUMBER 10/790,276 219.005-C1-US APPLICANT(S) Yamada et al.

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

FILING DATE GROUP ART UNIT 2825- 212 T March 1, 2004

<del></del>		U.S. PA	TENT DOCUMENTS			
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Oun	4,571,685	2/1986	Kamoshida	<b></b>		
air	6,055,463	4/2000	Cheong et al.			
Qi P	6,314,379	11/2001	Hu et al.			
$\widehat{L}^{VO}$	6,338,001	1/2002	Steffan et al.		-	
ahr	6,542,830	4/2003	Mizuno et al.			

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PATENT EXAMINER

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	9heet 1/2 of 2
ATTY. DOCKET NO.	SERIAL NUMBER
219.005-C1-US	10/790,276
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anr	3,614,608	10/1971	Giedd			
arc	4,949,162	8/1990	Tamaki et al.			
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arl	5,001,536	3/1991	Fukuzawa et al.		-	
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RIC.	5,493,236	2/1996	Ishii et al.			
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

APPLICANT (8)

Yamada et al.

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	Translation Yes/Mo
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04-062857	2/1992	Japan			
06-273297	9/1994	Japan			
07-066172	3/1995	Japan			
08-005528	1/1996	Japan			Y
08-313244	11/1996	Japan			
09-061142	3/1997	Japan			Y
10-281746	10/1998	Japan			
10-300450	11/1998	Japan			
<u>11-026343</u>	1/1999	Japan	-	- ====	
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Sheet SERIAL NUMBER ATTY. DOCKET NO. PTO-1449 (Modified) 219.005-C1-US 10/790,276 U.S. DEPARTMENT OF COMMERCE APPLICANT (9) PATENT AND TRADEMARK OFFICE Yamada et al. GROUP ART UNIT FILING DATE INFORMATION DISCLOSURE STATEMENT BY APPLICANT -2825-2/2) March 1, 2004 U.S. PATENT DOCUMENTS **EXAMINER** DOCUMENT DATE NAME SUB FILING NUMBER INITIALS CLASS CLASS DATE FOREIGN PATENT DOCUMENTS EXAMINER DOCUMENT SUB INITIALS NUMBER DATE COUNTRY CLASS CLASS 50-63990 5/1975 Japan Υ 57-6310 1/1982 Japan Υ 62-19707 1/1987 Y Japan 63-9807 1/1988 Japan OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) "An In-Line Contact and Via Hole Inspection Method Using Electron Beam Compensation Current", Yamada et al., IEEE 1999, Doc. No. 0-7803-5413-3/99/, available from http://www.fabsol.com/us/images/library/21.pdf DATE CONSIDERED EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication

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